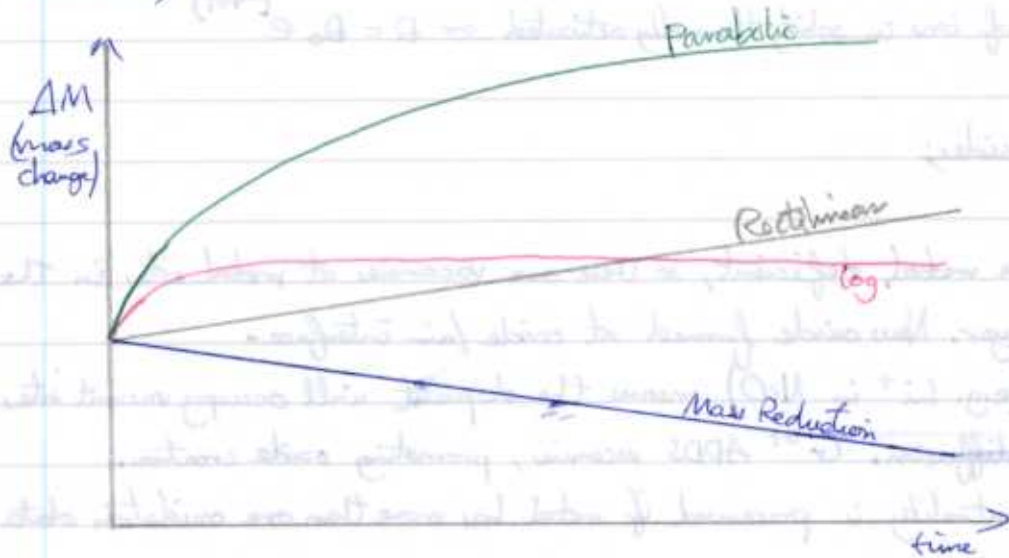


## High-Temperature Oxidation of Metals;

- \* Metals are corroded by dry gases at high temps. Hot  $\text{O}_2/\text{H}_2\text{S}/\text{SO}_2$  can react with the metal surface.
- \* Thermodynamics  $\Rightarrow$  Metal +  $\text{O}_2 \rightarrow$  Metal Oxide generally favourable.
- \* Kinetics  $\Rightarrow$  affected by oxide layer.

### Models;



\* PARABOLIC;  $-\frac{dm}{dt} = \frac{\text{constant}}{m}$   $\therefore (\Delta m)^2 = k_1 t$   
HIGH (T)

- oxide film covers surface, providing diffusional resistance.

\* LOGARITHMIC;  $-\frac{dm}{dt} = k_1 \log(k_2 t + k_3)$   
LOW (T)

- thin oxide provides complete protection from further oxidation once formed.

\* RECTILINEAR;  $-\frac{dm}{dt} = k_1$

$\Rightarrow$  Pilling-Bedworth (PB) ratio; relative vol. of oxide to pure metal.

PB < 1, oxide layer does not cover surface

PB  $\approx$  2, oxide layer contains cracks due to volume strain

\* Mass loss can occur if oxide is volatile and is removed from the surface.

### Parabolic Growth Rate Mechanism;

\*  $(\Delta m)^2 = kt$

\* rate of oxide growth limited by ion diffusion through oxide layer.

\* rate of oxide growth  $\Rightarrow \frac{dx}{dt} \propto \frac{D C_{O_2}}{x} \therefore (\Delta x)^2 = kt$

\* Diffusion of ions in solid; thermally activated so  $D = D_0 e^{(-E_a/RT)}$

### P-type Oxides;

\* These are metal deficient, so there are vacancies at metal sites in the oxide layer. New oxide formed at oxide/air interface.

\* Doping (e.g.  $Li^+$  in  $NiO$ ) means the dopant will occupy vacant site, reducing diffusion.  $Cr^{3+}$  adds vacancies, promoting oxide creation.

\* Charge neutrality is preserved if metal has more than one oxidation state.

### N-type Oxides;

\*  $O^{2-}$  quicker than  $M^{n+}$  diffusion so oxygen ion diffusion dominates kinetics.

\* Oxide layer forms at metal/oxide interface. This can cause tensile stress causing fracture of the oxide film.

### Prevention;

\* Dope oxide film

\* Alloy metal so good film is produced.